

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	wafer and in-line and QC and test and (data near mining) and yield	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 12:57
L2	5	wafer and in-line and test and (data near mining) and yield	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 12:58
L3	9044	tai.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/13 13:36
L4	8	3 and hung-en	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/13 13:36
L5	1416	438/14.ccls. and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/13 14:38
L6	94	5 and test and parameter and sample	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/13 14:38
S1	16	702/84.ccls. and database and test and correlation	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/31 13:19
S2	9	702/84.ccls. and database and test and analyze and correlation and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/27 09:56

S3	100	700/109.ccls. and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/31 13:58
S4	669	wafer and (quality near control) and analyzing	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/31 14:00
S5	108	(wafer and (quality near control) and analyzing) and parameter and lot and sample	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/31 14:19
S6	9	(quality adj control) same test same parameter same analyzing	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 08:59
S7	505	(quality adj control) and sample and parameter and search and database and analyzing	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/31 14:31
S8	40	((quality adj control) and sample and parameter and search and database and analyzing) and correlating and predicting	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/31 14:32
S9	113	((quality adj control) and sample and parameter and search and database and analyzing) and correlating	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/31 14:37
S10	31	((quality adj control) and sample and parameter and search and database and analyzing) and (((quality adj control) and sample and parameter and search and database and analyzing) and correlating) and wafer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/31 15:15
S11	200	wafer and in-line and yield and prediction	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/01 12:18
S12	16493	wafer and yield and analysis	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/01 12:19

S13	2711	(wafer and yield and analysis) and statistical	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/01 12:19
S14	665	((wafer and yield and analysis) and statistical) and regression	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/01 12:19
S15	601	((((wafer and yield and analysis) and statistical) and regression) and sample	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/01 12:20
S16	409	(((((wafer and yield and analysis) and statistical) and regression) and sample) and parameter	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/01 12:20
S21	2	"20050004773"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/13 14:37
S22	2	(wafer or sample) and (in-line near QC near test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 09:04
S23	2	wafer and (in-line near QC near test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 09:04
S24	51	wafer and in-line and QC and test	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/13 12:57
S25	2	"6618682".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/13 13:36

S26	2	"6618682".uref.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/13 10:34
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